
Long-Term Performance Data and Analysis of CIS/CIGS Modules Deployed Outdoors

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Outline

- ❑ Introduction
 - Rationale for thin-film CIS PV modules: cost - high efficiency
 - Identify loss modes and/or sources in CIS/CIGS modules
- ❑ Module deployment & Tests at NREL OTF
 - two manufacturers, types 'A' & 'B', on 3 separate testbeds
- ❑ Analyses 2 types of data,
 - STC & dark I-V standard diode devices
 - Real-time field data analysis
- ❑ Conclusions
 - FF degradation is predominant loss mode
 - ❖ Type 'A' can show very low rate to moderate loss rates
 - ⇒ Series-resistance increases symptomatic of A modules
 - ❖ Type 'B' can show very low loss rate to nominal loss rate
 - ⇒ Shunt increases & other subtle changes or failure mechanisms
 - Transient behavior observed especially after dark storage

Introduction

- ❑ Thin-film PV technologies (CIGS, CdTe, a-Si/nc-Si) are expected to achieve and compete for lowest cost per watt vs. bulk technologies (c-Si, poly-c-Si) largely because of economy in and costs of semiconductor materials usage;

- ❑ Copper indium diselenide (CIS) and/or gallium-alloyed CIGS photovoltaic (PV) modules achieve some of highest PV conversion efficiency of the thin-films:
 - Current state-of-the-art CIGS efficiency at Standard Test Conditions (STC):
 - ❖ cells attain 19.9%
 - ❖ modules ($\sim 0.4 - 0.5 \text{ m}^2$) attain $\sim 12\%$

- ❑ CIGS PV module stability issues need addressing
 - issues under damp/dry heat exposure
 - high-voltage bias applications for electrical power

Introduction: performance & reliability loss modes

□ FF losses:

- Series resistance (R_{se}) increases:
 - ❖ degradation of top TCO (ZnO) resistivity
 - ❖ CdS/CIS interface
- Shunt conductance (G_{sh})
- Diode qualities (A , J_0) & recombination

□ Voc losses:

- electronic carrier effects in CIS,
- band offsets, CdS/CIS interface

□ Isc loss modes not obvious, but possibilities:

- transparency of top TCO, EVA
- R_{se} increases are very large

Experimental Tests at OTF

- ❑ Two manufacturers of modules ‘A’ & ‘B’
 - glass/Mo/CIGS/CdS/ZnO/glass laminates
 - type A deployed beginning in 1988, 5 vintages
 - type B deployment began 2002
 - Other CIS manufacturers also at OTF but not reported
- ❑ Study CIS/CIGS modules deployed on 3 testbeds:
 - Single units, free-standing, long-term exposure, loaded at P_{max} (STC) with fixed resistor, 9 total
 - High Voltage Stress Testbed (HVST2) Array
 - ❖ consists of 2, bipolar strings, nominally ± 300 VDC open circuit
 - ❖ 12 type ‘A’ CIGS modules per string, 24 total
 - ❖ I-V traces monitored & loaded continuously with DAS
 - Performance & Energy Ratings Testbed (PERT)
 - ❖ I-V traces monitored & loaded continuously with DAS
 - ❖ A module 1997, B module 2002

PERT & HVST2 Array Module Deployment

❑ Performance & Energy Ratings Testbed (PERT)

- Open-air steel frame mounts, face due south, tilted at 40° latitude with respect to horizontal
- Meteorologic resources (Irr, module & air temps., etc)



PERT: viewed looking west

❑ Array: High-voltage stress test (HVST2)

- Same sensors as PERT, plus RH
- Elevated, frames electrically floated to measure HV leakage currents



HVST2 array: viewed looking east

Long-term free-standing single module deployment

- ❑ loaded with fixed resistor,
- ❑ 9 modules total
- ❑ Also tilted at latitude angle, facing south
- ❑ open-air steel rack mounts

1988 A module installed 20 years



Long-term exposure rack seen looking east

Data Analysis: STC or dark at 25°C

- ❑ Single I-V curves at STC or dark at 25°C
 - STC data: SPIRE, LACSS or SOMS
 - ❖ LACSS & SOMS use P/S to drive I-V traces
 - Module data normalized to unit area cell (J-V):
 - ❖ dividing voltage by series cell count (N_{cell})
 - ❖ dividing current by area per cell ($A_{cell} = A_{perArea} / N_{cell}$)
 - Standard PV device diode circuit model with
 - ❖ parasitic series resistance (R_{se}) and shunt conductance (G_{sh})
 - ❖ determined R_{se} , G_{sh} (dark) allows raw data to be corrected and then to derive A , J_0

Diode Analysis: Rse, diode Q, Gsh, J₀

□ Diode Eq. $J = J_0 * [e^{q(V-RseJ)/AkT} - 1] + G_{SH}V - J_L$

➤ Derive 3-pnt slopes dV/dJ (Rse) or dJ/dV (Gsh) & correct data for series & shunt

❖ dV/dJ vs. $1/J$ or $1/(J+J_{light})$

⇒ Intercept = Rse,

⇒ slope = A (k_BT/q)

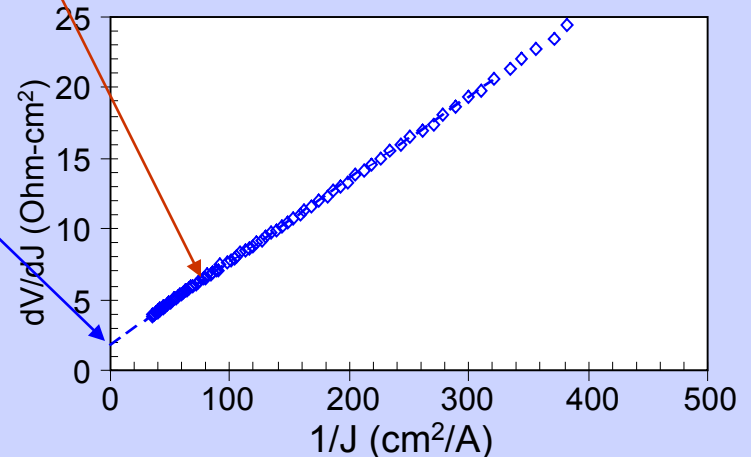
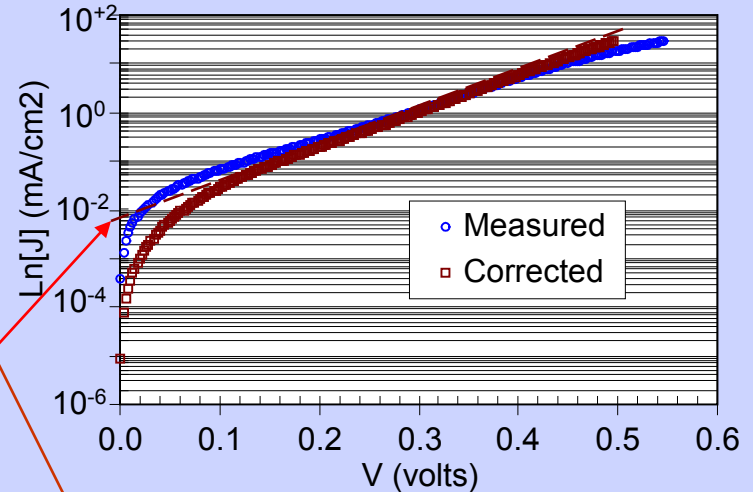
❖ Gsh: from dJ/dV minimum near 0 V

❖ $V \rightarrow V_{cor} = V - RseJ,$

$J \rightarrow J_{cor} = J - GV$

❖ $Ln(J_{cor}) - V_{cor} \Rightarrow J_0,$

❖ Also A ⇒ slope V vs. LnJ



Data Analysis: PERT & HVST2

- ❑ Real-time outdoor data measured in situ with programmable electronic loads & DAS
 - I-V power parameters (V_{oc} , FF, etc.) data condensed
 - ❖ segregated into narrow irradiance bands ($\pm 25 \text{ W/m}^2$) for all illumination intensities,
 - ❖ Linear regression vs. module temperature (T_{mod}) each bin:
 - ⇒ Parameter Y: $Y(T_{mod}) = Y_0 + dY/dT_{mod} * T_{mod}$
 - select bands analyzed 250, 500, 1000 W/m^2 , vs. time
 - ❖ averaged to cover 3 select windows for $\pm 75 \text{ W/m}^2$ span
 - ❖ cover most of energy-producing field conditions
 - Data partitioned to 3-month intervals
 - ❖ Power parameters, Rseries, diode Q factor derived for each
 - ❖ Changes in power parameters vs. time calculate

Single module data at STC (SPIRE or LACSS)

❑ Manufacturers A & B:

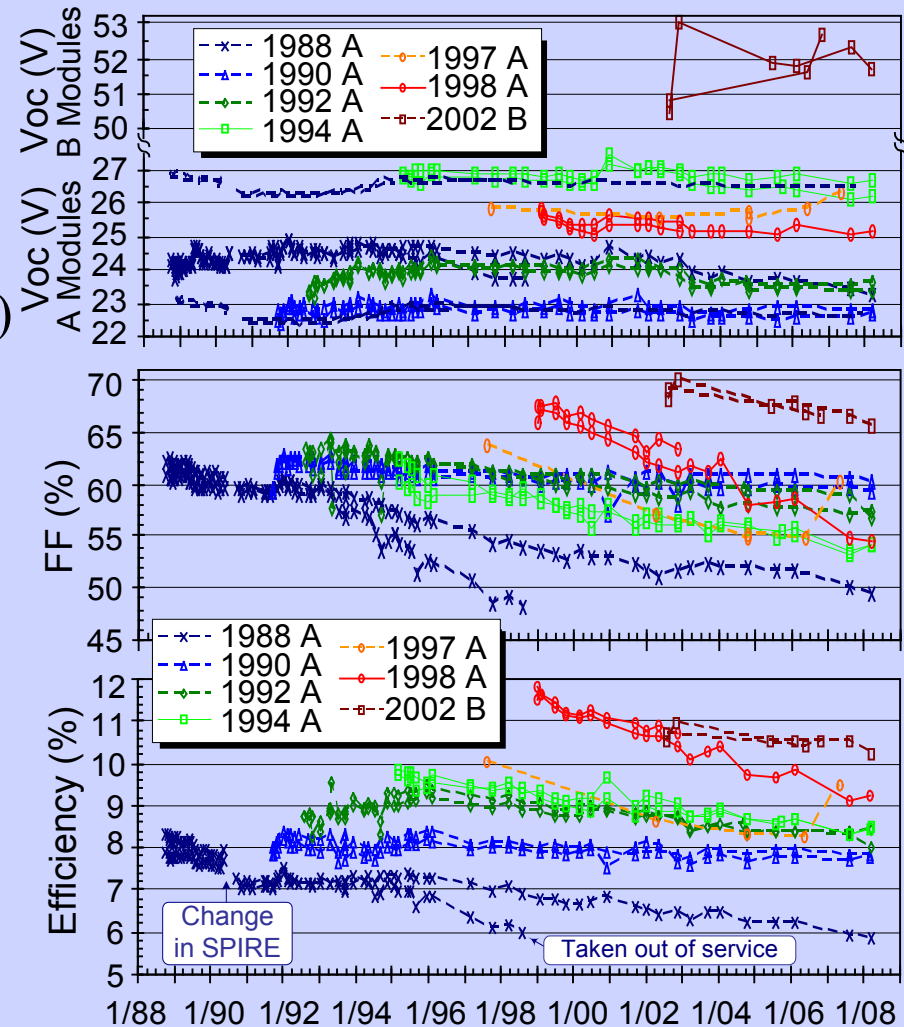
- A: (5 vintages) 1988, 1990, 1992, 1994, 1998;
- B: 2002

❑ A module initial efficiency

- from 8% (1988) to ~ 11-12% (1998)
- Low loss rates earlier 1%/yr or less
- stability became issue when initial efficiency exceeded ~ 9%:
 - ❖ FF losses account for most decline
 - ❖ Voc increases in initial years, partly offset FF losses, but subsequently can degrade

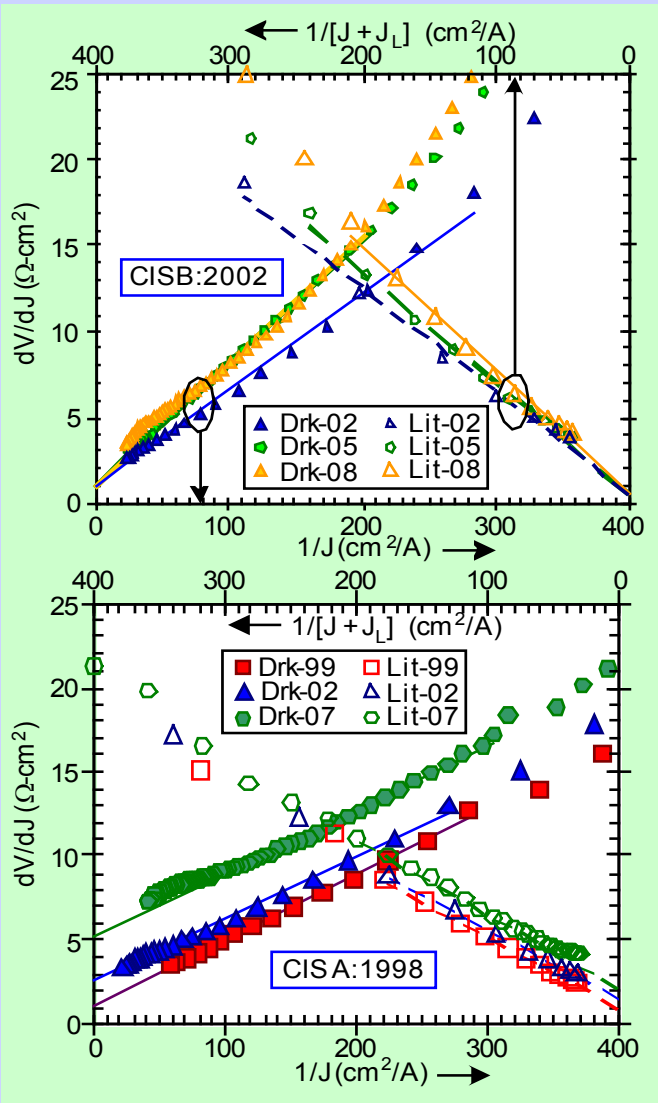
❑ B module initial efficiency ~11%

- slight decline mostly in FF, partly offset by Voc increase during first years



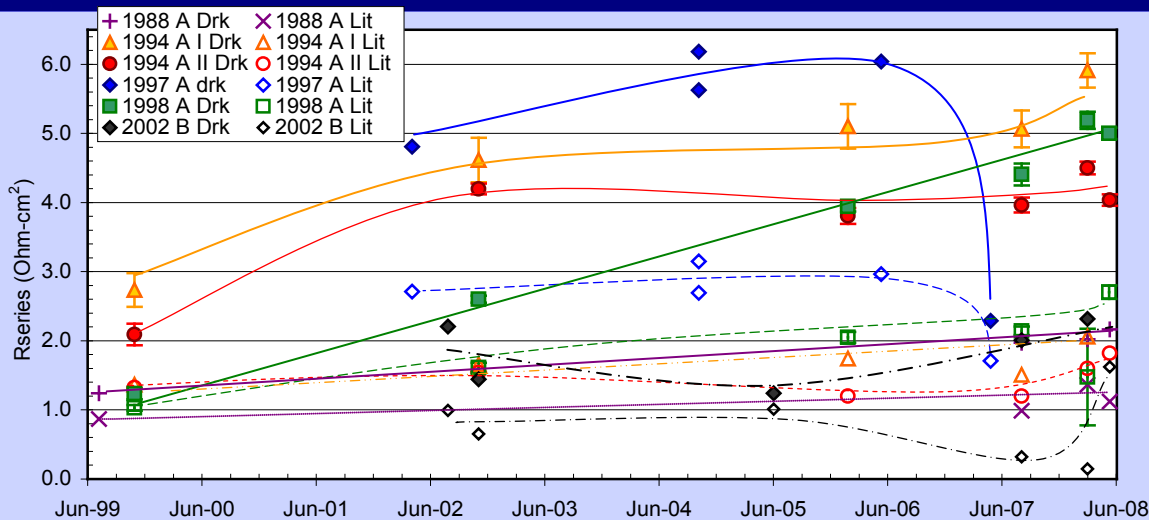
Data: series resistance changes single modules

□ Dark & Light Slopes dV/dJ plotted vs.



- $1/J$ for dark data read along lower ordinate axis
- $1/(J+J_{\text{Light}})$ for light data, read along upper ordinate axis
- 2002 B in upper pane ('02, '05, '08)
1998 A in lower pane ('99, '02, '07)
- For 2002 B no increase in R_{se} intercept in both dark & light data over time
 - ❖ curvature suggestive of other effects
- For 1998 A substantial increase in R_{se} intercept in dark ($\sim 4 \Omega\text{-cm}^2$) & some in light ($1\text{-}2 \Omega\text{-cm}^2$) data with time

Series resistance data, STC/dark I-V on LACSS



- Dark (filled), Light (open) symbols
- Long-term exposure rack modules shown, with A & B from PERT occasionally tested on LACSS
- Manually drawn trend lines shown as guide

□ 1988 A

- Dark increase ~ 1.2 to $2.0 \Omega\text{-cm}^2$
- Light increase ~ 0.8 to $1.4 \Omega\text{-cm}^2$

□ 1994 A #1 & #2

- Dark increase $\sim 2.1\text{--}2.8$ to $4.5\text{--}6 \Omega\text{-cm}^2$
- Light increase ~ 1.4 to $2.0 \Omega\text{-cm}^2$

□ 1998 A

- Dark increase: 1.2 to $5 \Omega\text{-cm}^2$
- light increase: 1 to $2.8 \Omega\text{-cm}^2$

□ 1997 A (PERT)

- Dark increase (2002–06): $1 \Omega\text{-cm}^2$
- light increase (2002–06): $\frac{1}{2} \Omega\text{-cm}^2$

- (1997 A) substantial metastable drop in R_s of 3.5 or $1 \Omega\text{-cm}^2$ for dark or light, while module lay indoors 1 year

- Also reflected in performance (in & out)

□ 2002 B

- Dark 1.5 to $2.3 \Omega\text{-cm}^2$

□ Light 0.6 to $1.4 \Omega\text{-cm}^2$

□ 2002 B (PERT)

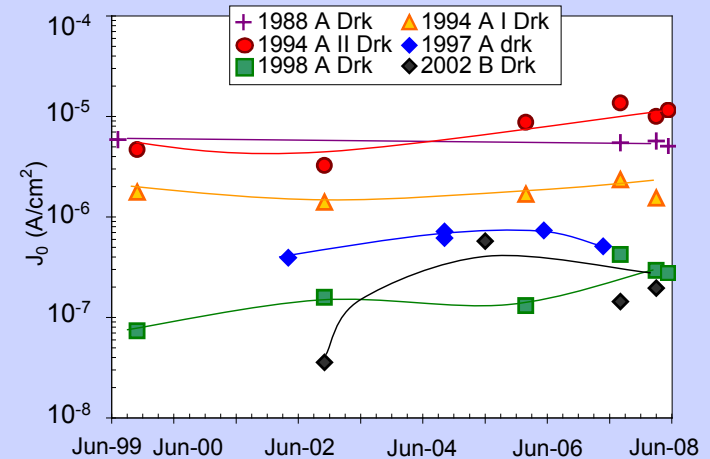
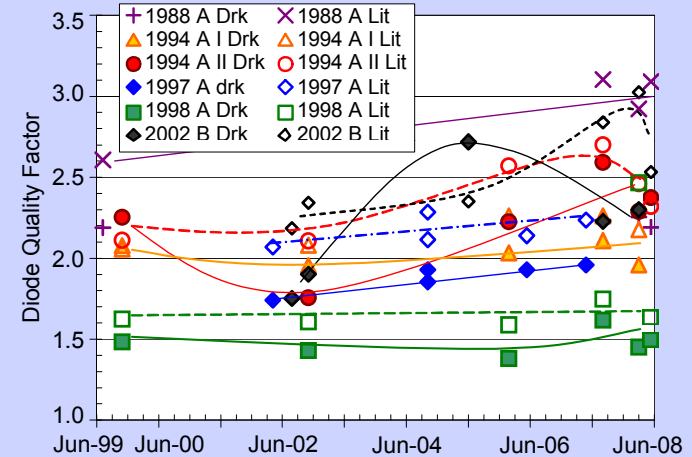
- Dark nearly no change $\sim 1.8 \Omega\text{-cm}^2$
- light nearly no change $\sim 1.5 \Omega\text{-cm}^2$

□ R_{se} increases impact type A more than type B because of higher J_{sc} for A (STC)

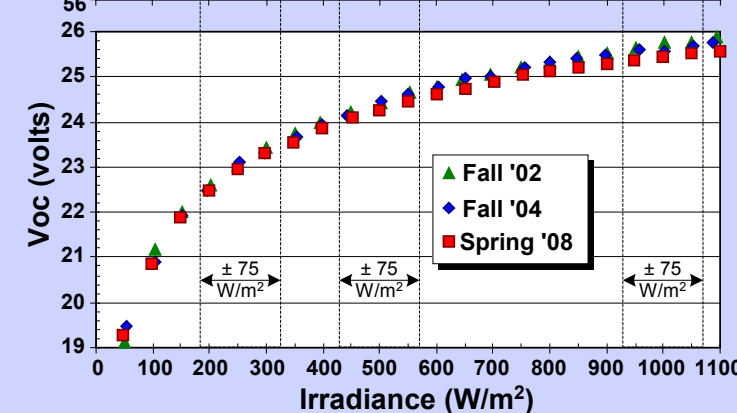
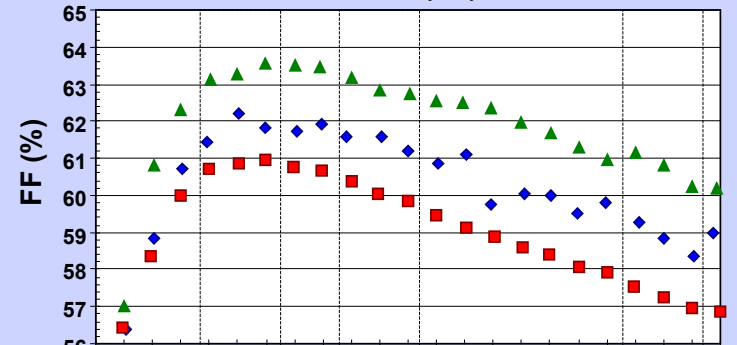
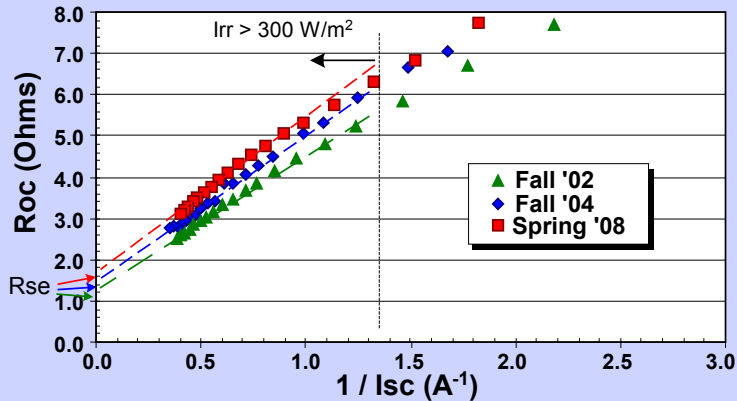
- $\sim 30 \text{ mA/cm}^2$ for A, $\sim 24 \text{ mA/cm}^2$ for B

Diode J_0 , A factors, STC/dark I-V on LACSS

- ❑ A from dark or light $dV/dJ-1/J$ data;
- ❑ J_0 from dark $\text{Log}(J_{\text{cor}}) - V_{\text{cor}}$
- ❑ A modules (over 8-years period)
 - Quality factors changes between negligible to 20% increases
 - Dark J_0 increases small, highest factor of x2
- ❑ B modules (over 5-year period)
 - Quality factors show more substantial gain, 25%-30%
 - J_0 changes by mult factor up to 40
 - More detail picture show 2-diode type behavior, primary weakening



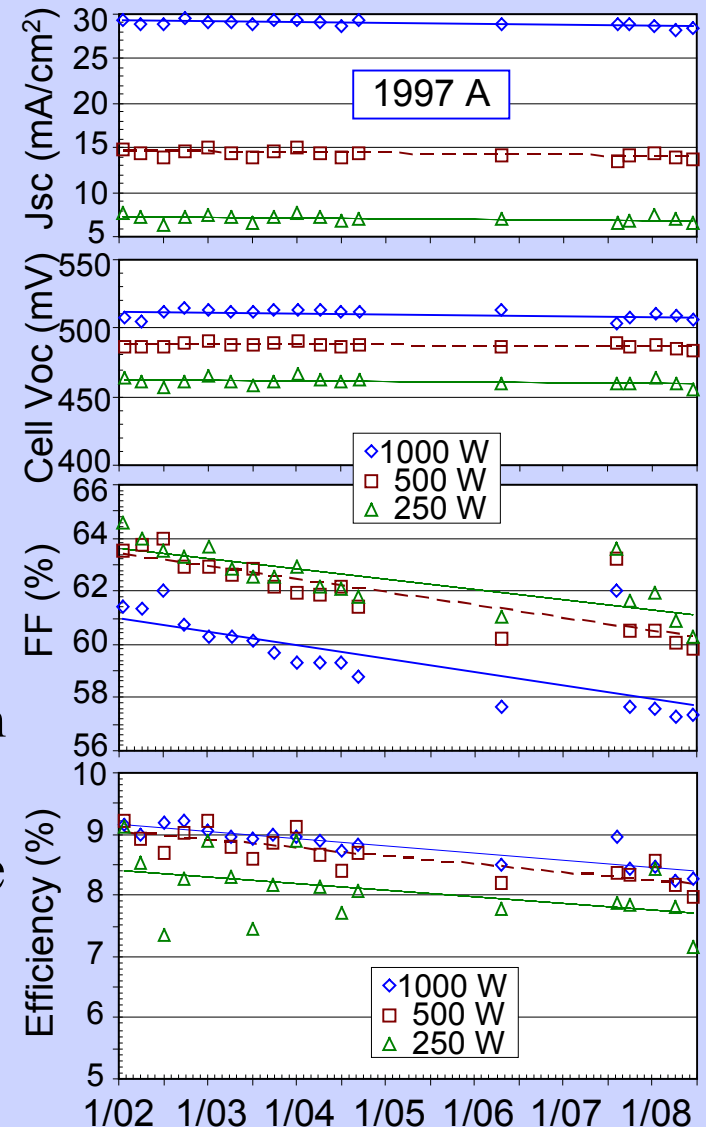
Sample PERT 1997 A Data: Across Irradiance



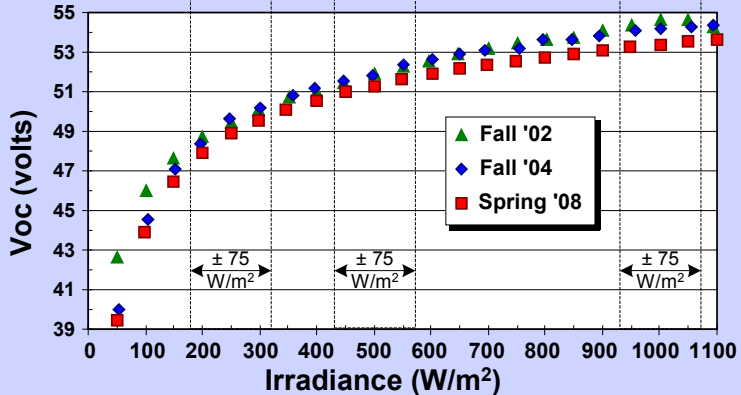
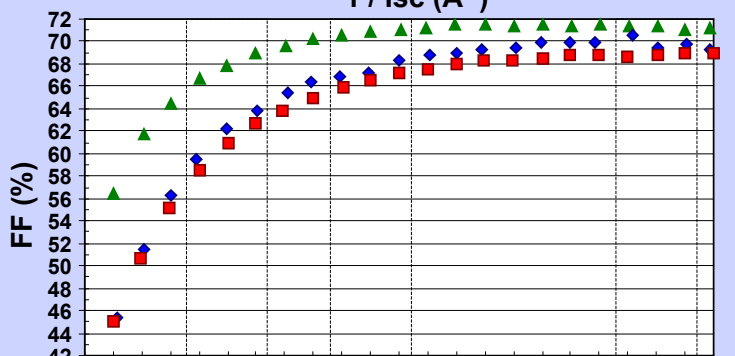
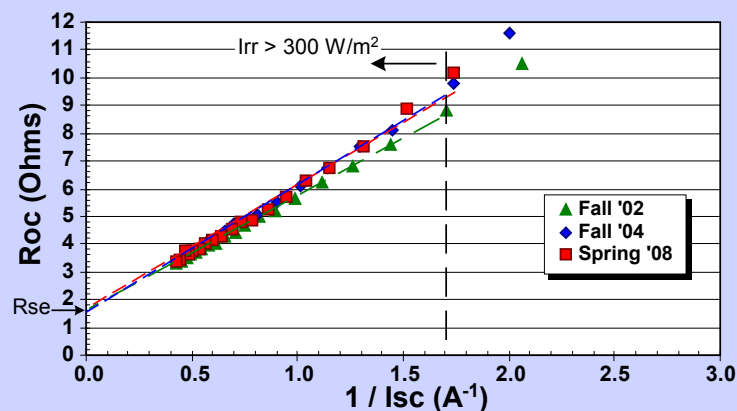
- ❑ Roc(Irr), FF(Irr) & Voc(Irr) from top to bottom
 - Segregated data by irradiance bins ± 25 W/m^2 ,
 - Linear regression with T_{mod} , evaluated at 25°C ;
 - data partitioned into 3-month semesters 2002-08
 - Examine 3 irradiance ranges, each spanning ± 75 W/m^2 , at low (250 W/m^2), mid (500 W/m^2), & high (1000 W/m^2) intensities
- ❑ Sample data for Fall 2002, Fall 2004 & Spring 2008
- ❑ Voc vs. Irradiance data: slight drop with time,
- ❑ FF vs. Irradiance data
 - Peak in FF at 250 W/m^2 , followed by linear decline toward high irradiance typical of many modules consistent with compromise between series resistance loss vs. optical transparency
 - exhibit 5% relative decline for all irradiance above 250 W/m^2 , consistent with series resistance (R_{se}) increase
- ❑ Roc vs. $1 / I_{\text{sc}}$ data intercept gives R_{se}
 - increase of about 0.6 ohms, or 50% relative

PERT 1997 A Data: Power Parameters vs. time

- Data in 3 irradiance bands, low to high irradiance, plotted vs. time
 - Voc & Jsc normalized to cell level
 - Performance ($\delta\text{Eff} / \delta t$) loss rates
 - ❖ 1.3 %/yr to 1.5 %/yr all 3 bands
 - FF degradation rates dominate loss
 - ❖ 0.6 %/yr to 0.8 %/yr
 - ❖ Lower FF at high irradiance coupled with higher FF at low irradiance consistent with series resistance as failure mode
 - Jsc decline next discernable loss mode
 - ❖ 0.4%/yr at 1000 W/m², or 0.7%/yr lower irradiance



Sample PERT 2002 B Data: Across Irradiance



- ❑ Roc(Irr), FF(Irr) & Voc(Irr) from top to bottom
 - Segregated data by irradiance bins $\pm 25 \text{ W/m}^2$,
 - Linear regression with T_{mod} , evaluated at 25°C ;
 - data partitioned into 3-month semesters 2002-08
 - Examine 3 irradiance ranges, each spanning $\pm 75 \text{ W/m}^2$, at low (250 W/m^2), mid (500 W/m^2), & high (1000 W/m^2) intensities
- ❑ Sample data for Fall 2002, Fall 2004 & Spring 2008
- ❑ Voc vs. Irradiance data: small but discernable drop vs. time lately
- ❑ FF vs. Irradiance data, between 2002 and 2008
 - Plateau behavior in FF from low to high increasing irradiance, not typically consistent with series resistance loss mode, but Gsh losses
 - 10 % relative decline at 250 W/m^2 ,
 - 5 % relative decline at 500 W/m^2 ,
 - 3 % relative decline at 1000 W/m^2 ,
- ❑ Rse: Roc vs. $1/I_{\text{sc}}$ data intercept
 - No apparent significant increase

PERT 2002 B Data: Power Parameters vs. time

□ Data in 3 irradiance bands, low to high irradiance, plotted vs. time

➤ Voc & Jsc normalized to cell level

➤ Performance ($\delta\text{Eff} / \delta t$) loss rates

❖ -2.3 %/yr low, -1.8 %/yr mid, -1.0 %/yr high irradiance

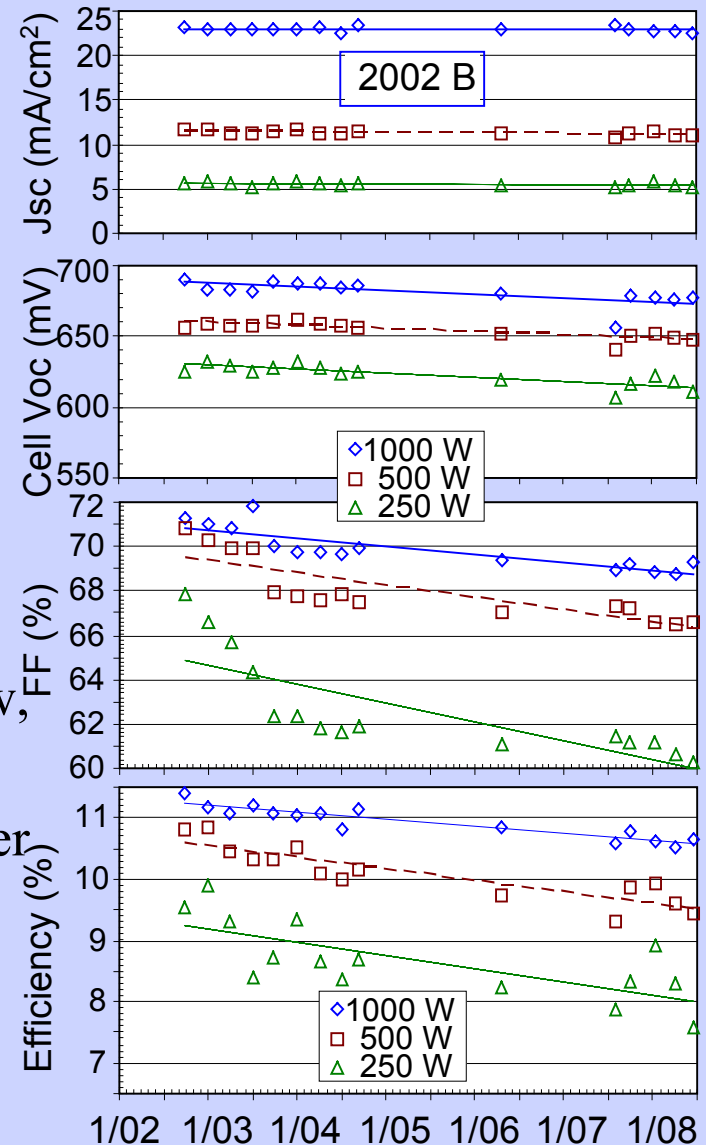
➤ FF degradation rates dominate performance loss rates

❖ -1.31 %/yr, -0.80 %/yr, -0.51 %/yr at low, mid, high irradiance

❖ Low & mid irradiance losses appear larger initially

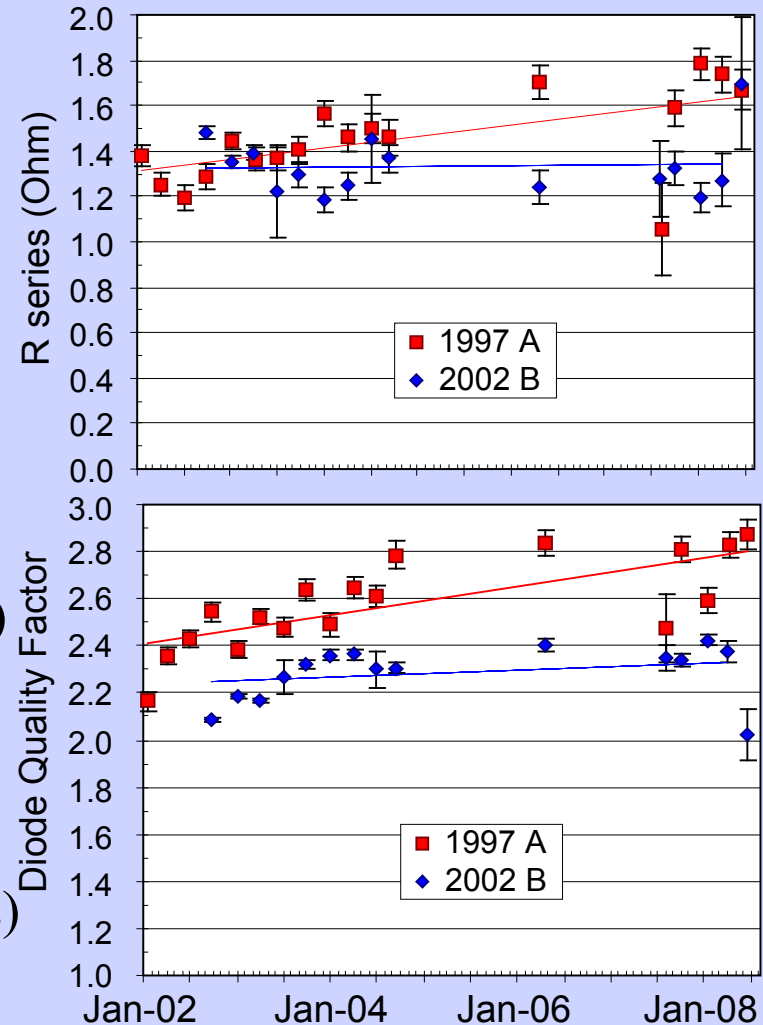
➤ Voc declines $\sim -0.4\%/yr$

➤ Jsc declines $-0.7\%/yr$ at low & mid

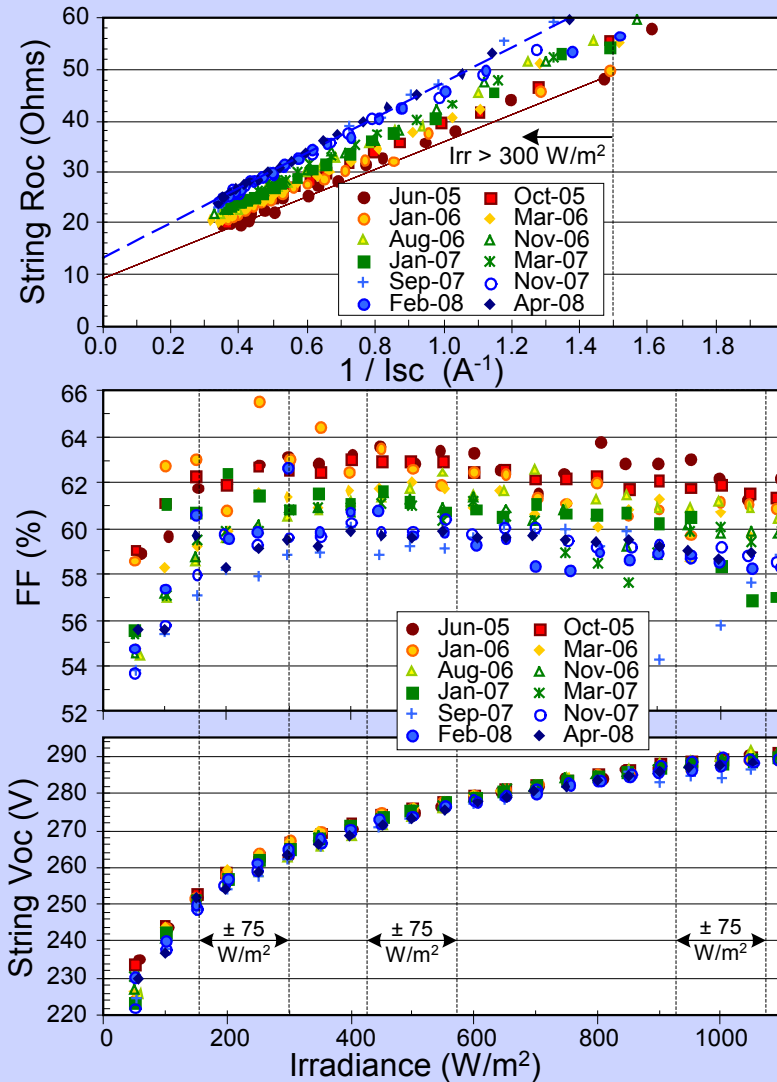


PERT 1997 A & 2002 B: Rse, A Data vs. time

- ❑ Rseries extrapolated for $I_{rr} > 300 \text{ W/m}^2$ for each set $R_{oc}(I_{rr})-1/I_{sc}(I_{rr})$ each semester
 - if regression includes lower I_{rr} does not alter results significantly except scatter
- ❑ A module
 - Rseries degrades (increases) 0.4 to 0.5 ohms in over 6 years
 - Point at Aug-2007 correlates with metastable performance
 - Diode quality factor degrades (increases) at rate $\sim 2.5 \text{ \%/yr}$
- ❑ B module
 - Rseries: statistically no change
 - Diode quality factor degrades (increases) at rate $\sim 0.7 \text{ \%/yr}$

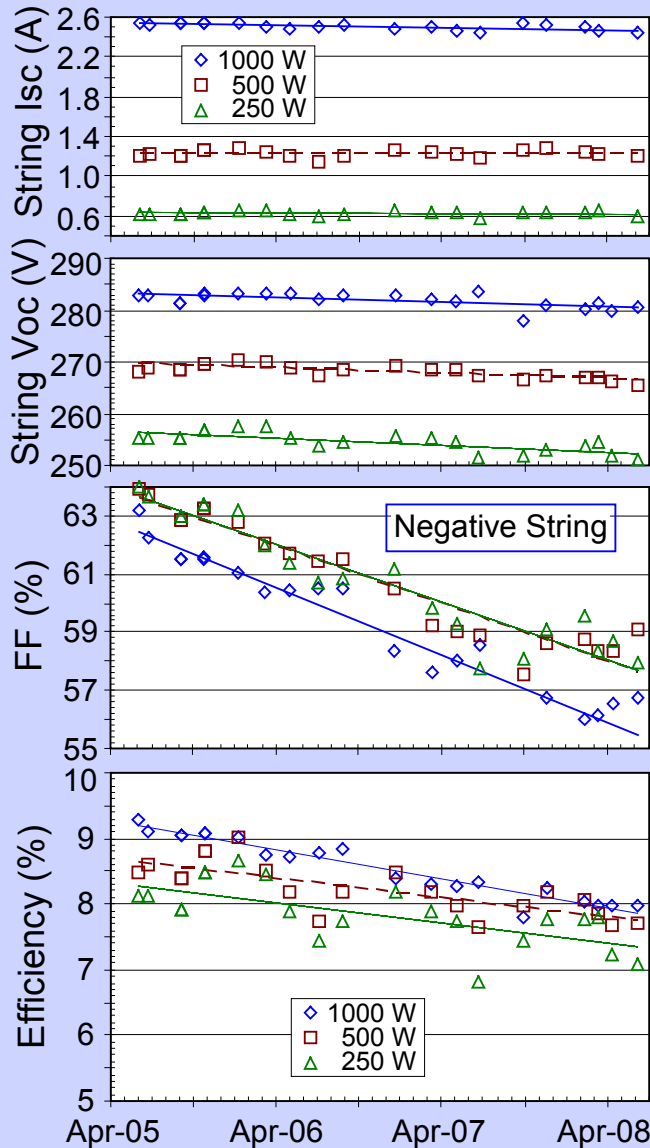


(+ String) Sample HVST2 Data : Across Irradiance



- ❑ Roc(Irr), FF(Irr) & Voc(Irr) from top to bottom
 - segregated data by irradiance bins $\pm 25 W/m^2$, 3 irradiance ranges, at low, mid, & high intensities, regression to evaluate parameters at $25^\circ C$
- ❑ data for Jun '05 thru Apr '08 color coded in rainbow-spectral-sequence:
 - red \Leftrightarrow earlier '05, blue \Leftrightarrow latter '08
- ❑ Voc vs. Irradiance data:
 - slight but palpable drop vs. time
- ❑ FF vs. Irradiance data exhibit 10% relative decline between Jun '05 and Apr '08
- ❑ Rse: Roc vs. $1/I_{sc}$ data intercept
 - Obvious shift in Rse to higher values vs. time by $\sim 4-5$ ohms

HVST2 array Power Parameters vs. time: (– string)

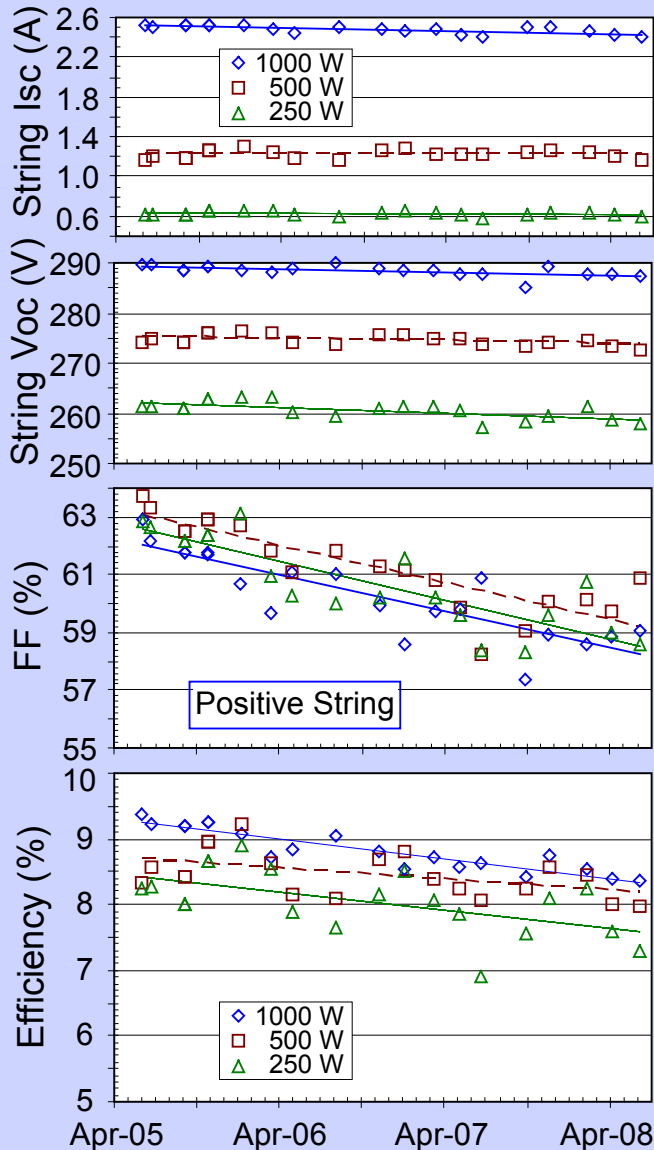


- ❑ Data in 3 select irradiance bands shown,
 - adjacent bands averaged, span $\pm 75 \text{ W/m}^2$
 - Time span: Apr. 2005 – Jul. 2008
- ❑ Efficiency loss rates moderately high
- ❑ FF degradation rates lead
- ❑ Voc degradation also discernable
 - initial $\sim 284 \text{ V}$ (6 V less than + string)
- ❑ Some Isc loss rate at high irradiance

Negative string summary loss rates

	250 W/m ² (%/yr)	500 W/m ² (%/yr)	1000 W/m ² (%/yr)
Eff	-3.7 ± 0.95	-3.4 ± 0.68	-4.8 ± 0.29
FF	-3.1 ± 0.24	-3.1 ± 0.22	-3.7 ± 0.30
Voc	-0.52 ± 0.12	-0.36 ± 0.07	-0.30 ± 0.09
Isc	-0.24 ± 0.76	0.15 ± 0.66	-0.99 ± 0.21

HVST2 array Power Parameters vs. time: (+ string)

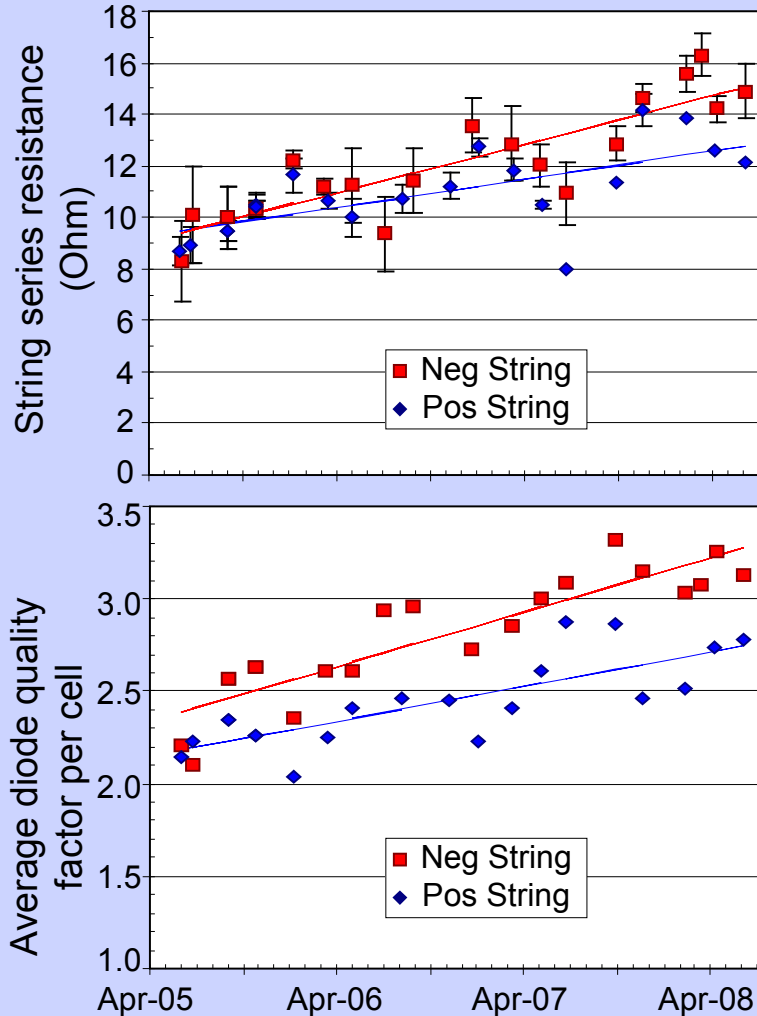


- ❑ Data in 3 select irradiance bands shown,
 - adjacent bands averaged, span $\pm 75 \text{ W/m}^2$
 - Time span: Apr. 2005 – Jul. 2008
- ❑ Efficiency loss rates moderately high, but discernable lower than for negative string
- ❑ FF degradation rates lead, then Voc
- ❑ Most loss rates smaller than for Voc loss lower than negative at high irradiance
- ❑ Isc loss at high irradiance

Positive string summary loss rates

	250 W/m ² (%/yr)	500 W/m ² (%/yr)	1000 W/m ² (%/yr)
Eff	-3.3 ± 1.15	-2.0 ± 0.83	-3.3 ± 0.34
FF	-2.2 ± 0.31	-2.0 ± 0.29	-2.0 ± 0.30
Voc	-0.45 ± 0.12	-0.20 ± 0.07	-0.21 ± 0.07
Isc	-0.93 ± 0.86	0.33 ± 0.77	-1.13 ± 0.29

HVST2 \pm strings: Rse, A Data vs. time



□ Rseries 2005 to 2008

- Both strings start out at nearly identical values (~ 9 ohms), but increase 4-6 ohms with time
 - ❖ Growth in negative string's Rse outpaces the positive string by 2 ohms in 3 years
- intercept derived for $I_{rr} > 300 \text{ W/m}^2$
 - ❖ but including lower intensities produces similar results with larger scatter

□ Diode Q factors degradation (growth) rates:

- -string: 12 %/yr
- +string 7.5 %/yr

Conclusions: Performance Loss Rates @ STC

□ Long-term exposure rack modules:

➤ Type A, SPIRE

- ❖ (1 of 1988, 2 each 1990, 1992, 1994, 1998)
- ❖ Predominantly FF losses via Rse increases, followed by Voc loss
- ❖ Isc losses likely not significant

➤ Type 2002 B

- ❖ (2 modules SPIRE & LACSS, includes one on PERT)
- ❖ Loss rate in FF counter-balanced by increase rate in Voc

Module Type	$\Delta\text{Voc}/\text{Voc}$ (%/yr)	$\Delta\text{Isc}/\text{Isc}$ (%/yr)	$\Delta\text{FF}/\text{FF}$ (%/yr)	$\Delta\text{Eff} / \text{Eff}$ (%/yr)	TIMELINE
1988 A	-0.25%	0.36%	-1.09%	-0.90%	Nov-90 –Mar-08
1990 A	-0.02%	0.01%	-0.24%	-0.26%	Oct-91–Mar-08
1992 A	-0.05%	0.19%	-0.55%	-0.43%	Aug-92–Mar-08
1994 A	-0.08%	-0.11%	-0.84%	-1.01%	Mar-95–Mar-08
1998 A	-0.24%	-0.15%	-1.89%	-2.19%	Jan-99–Mar-08
2002 B	0.57%	-0.16%	-0.83%	-0.40%	Aug-02–Mar-08

Conclusions: Performance Loss Rates PERT

- Average * loss rate 1997 A: -1.4 %/yr,
 - FF declines from Rse increase dominate performance loss
 - Jsc decline next more important sizeable loss

	Module	250 W/m ² (%/yr)	500 W/m ² (%/yr)	1000 W/m ² (%/yr)
Eff	1997 A	-1.3 ± 0.08	-1.5 ± 0.04	-1.3 ± 0.03
FF		-0.60 ± 0.13	-0.75 ± 0.13	-0.84 ± 0.20
Voc		-0.07 ± 0.00	-0.05 ± 0.00	-0.13 ± 0.00
Jsc		-0.68 ± 0.06	-0.71 ± 0.06	-0.37 ± 0.04

- Average * loss rate 2002 B: -1.7 %/yr
 - FF declines dominate performance loss, likely from shunt increase,
 - Jsc decline next important sizeable loss, but Voc loss larger at high irradiance

	Module	250 W/m ² (%/yr)	500 W/m ² (%/yr)	1000 W/m ² (%/yr)
Eff	2002 B	-2.3 ± 0.09	-1.8 ± 0.04	-1.0 ± 0.02
FF		-1.31 ± 0.29	-0.80 ± 0.15	-0.51 ± 0.09
Voc		-0.45 ± 0.00	-0.35 ± 0.00	-0.38 ± 0.00
Jsc		-0.74 ± 0.04	-0.72 ± 0.04	-0.13 ± 0.05

* Average over 3 irradiance windows (250 W/m², 500 W/m², 1000 W/m²)

Conclusions: Performance Loss Rates HVST2

- Decline rates averaged * Negative string degradation at -4.0 %/yr

	250 W/m ² (%/yr)	500 W/m ² (%/yr)	1000 W/m ² (%/yr)
Eff	-3.7 ±0.95	-3.4 ±0.68	-4.8 ±0.29
FF	-3.1 ±0.24	-3.1 ±0.22	-3.7 ±0.30
Voc	-0.52 ±0.12	-0.36 ±0.07	-0.30 ±0.09
Isc	-0.24 ±0.76	0.15 ±0.66	-0.99 ±0.21

- Decline rates averaged * Positive string degradation at -2.9 %/yr

	250 W/m ² (%/yr)	500 W/m ² (%/yr)	1000 W/m ² (%/yr)
Eff	-3.3 ±1.15	-2.0 ±0.83	-3.3 ±0.34
FF	-2.2 ±0.31	-2.0 ±0.29	-2.0 ±0.30
Voc	-0.45 ±0.12	-0.20 ±0.07	-0.21 ±0.07
Isc	-0.93 ±0.86	0.33 ±0.77	-1.13 ±0.29

- High-voltage stress may lead to higher degradation in these A (2003) modules

 - Higher loss may also be result of manufacturer process, probably both

- FF decline & Rseries increases dominate performance loss/failure mode:

 - 11%/yr and 20%/yr, for the positive and negative strings, respectively

- Degradation rates consistent with earlier analysis done via PTC regression method

 - * Average over 3 irradiance windows (250 W/m², 500 W/m², 1000 W/m²)

Acknowledgements

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- Thank you for your attention